

Lecture 2a

①

Michelson's Interferometer

Interferometer - device that can measure lengths or changes in length w/ great accuracy by using interference fringes.

(show slides)

- Light leaves point P on extended source S.
- It then encounters a beam splitter, which transmits half of incident light & reflects other half.

(2)

- At beamsplitter M , light divides into two waves.
- one ^{part} goes toward mirror M_1 .
- other part goes toward mirror M_2 .
- waves are then ~~entirely~~ reflected @ mirrors & sent back along directions of incidence.
- Observer sees a pattern of curved or approximately straight interference fringes (show slides)

Question: what is difference in path length traveled by two light waves when they recombine @ telescope?

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Answer: $2d_2 - 2d_1$

Anything that changes this path length difference causes a change in phase difference between two observed waves.

- ~~For~~ For example, suppose mirror M_2 is moved a distance $\frac{1}{2}\lambda$. What is change in path length difference?

Then causes fringe pattern to shift by one fringe.

(4)

— Shift in fringe pattern can also be caused by insertion of thin transparent material into optical path of one of the mirrors.

— If material has thickness L & index of refraction n , then # of wavelengths along light's to-and-fro path through material is

$$N_m = \frac{2L}{\lambda/n} = \frac{2Ln}{\lambda}$$

of wavelengths in same thickness ^{2L} of air is

$$N_a = \frac{2L}{\lambda}$$

(5)

phase change in terms of
of wavelengths λ

$$N_m - N_a = \frac{2Ln}{\lambda} - \frac{2L}{\lambda}$$
$$= \frac{2L}{\lambda} (n-1)$$

- Can then use this \uparrow fringe ^{change in}
pattern to measure thickness L
of material in terms of λ .
(count # of fringes through
which material causes
pattern to shift.)

- This type of measurement is
so precise that it is now
used as the standard for
the meter (expressed in terms
of # of wavelengths of
monochromatic red light)

Ch. 36 - Diffraction

⑥

- We previously learned that interference + diffraction occur when light is incident on a double slit (Young's interference experiment)
- Now we learn about another effect when there is a single slit (or a sharp edge).
- diffraction occurs whenever light encounters edge of an object.

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Goal is now to figure out
location of minima from a
single slit,

(show figure from slides)

- Suppose light has wavelength λ
& slit has width a

- When diffracted light reaches
screen, it produces ~~an~~ diffraction
pattern of bright & dark fringes
on the screen.

- Before doing anything, note
that central bright fringe
comes about b/c all points
in slit travel about same distance
& are thus in phase (show slides)

(8)

Strategy for locating minima

— pair up all rays coming through the slit & then find conditions that cause them to cancel

1) Divide slit into two zones of equal widths $a/2$.

2) Extend light rays r_1 & r_2

Want wavelets from these two points to cancel each other.

We should compute path length difference:

To produce 1st dark fringe, rays r_1 & r_2 should be out of phase by $\pi/2$.

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Simplify calculation by allowing screen separation D to be much larger than slit width a .

- use approximation from before (rays r_1 & r_2 are approx. parallel)

(show slides for approx.)

- path length difference by simple geometry is $\frac{a}{2} \sin \theta$

- can repeat this analysis for any other pairs of rays @ corresponding points in two zones & extending to P_i .

- Each such pair of rays has same path length difference: $\frac{a}{2} \sin \theta$.

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Setting common path ^{length} difference to $\frac{\lambda}{2}$

then gives

(for dark fringes)

$$\frac{a}{2} \sin \theta = \frac{\lambda}{2}$$

$$\Rightarrow a \sin \theta = \lambda \quad (\text{locating 1st minimum})$$

gives angle θ of 1st dark fringe above & below central axis.

- Now we want to find second minima.

- Divide slit into 4 zones of equal width.

(show slides)

path length differences between r_1, r_2 & r_2, r_3 & r_3, r_4 should all = 0.

(11)

Approximate $D \gg a$ as before
(show slides)

- path length diff. between r_1 & r_2 is

$$\frac{a}{r} \sin \theta.$$

same for other pairs.

Dark fringes then occur @

$$\frac{a}{r} \sin \theta = \frac{\lambda}{2}$$

↑ corresponding to
destructive
interference.

$$\Rightarrow a \sin \theta = 2r\lambda$$

Can continue this to find all higher order
(dividing into smaller zones) minima.

then we get that minima are @ $a \sin \theta = m\lambda$
for $m=1, 2, 3, \dots$

(12)

In a single slit diffraction experiment, dark fringes are produced where path length differences between top & bottom rays are equal to $\lambda, 2\lambda, 3\lambda, \dots$

Question: Suppose diffraction pattern is produced by sending blue light through narrow slit.

~~Do~~ Do minima move away from or toward center when shifting to blue light

if we (a) shift to yellow light

(b) decrease slit width?

(both expand)